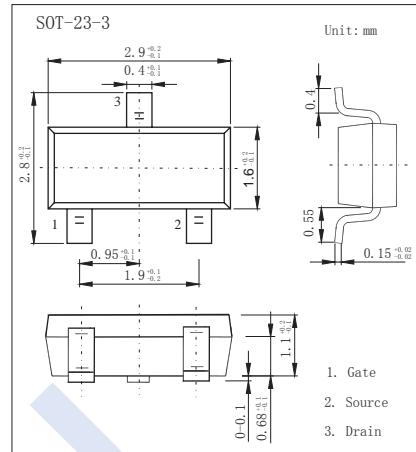
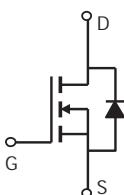


N-Channel Enhancement MOSFET

2KK5006DS

■ Features

- $V_{DS(V)} = 30V$
- $I_D = 5.8 A (V_{GS} = 10V)$
- $R_{DS(ON)} < 28m\Omega (V_{GS} = 10V)$
- $R_{DS(ON)} < 33m\Omega (V_{GS} = 4.5V)$
- $R_{DS(ON)} < 52m\Omega (V_{GS} = 2.5V)$



■ Absolute Maximum Ratings $T_a = 25^\circ C$

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current $T_a=25^\circ C$	I_D	5.8	A
$T_a=70^\circ C$		4.9	
Pulsed Drain Current *	I_{DM}	30	
Power Dissipation $T_a=25^\circ C$	P_D	1.4	W
$T_a=70^\circ C$		1	
Thermal Resistance.Junction- to-Ambient	R_{thJA}	125	$^\circ C/W$
Thermal Resistance.Junction- to-Case	R_{thc}	60	$^\circ C/W$
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^\circ C$

* Repetitive rating, pulse width limited by junction temperature.

2KK5006DS■ Electrical Characteristics $T_a = 25^\circ\text{C}$

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V_{DSS}	$I_D=250 \mu\text{A}, V_{GS}=0\text{V}$	30			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=24\text{V}, V_{GS}=0\text{V}$			1	μA
		$V_{DS}=24\text{V}, V_{GS}=0\text{V}, T_J=55^\circ\text{C}$			5	
Gate-Body leakage current	I_{GSS}	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			± 100	nA
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS}=V_{GS}, I_D=250 \mu\text{A}$	0.7	1.1	1.4	V
Static Drain-Source On-Resistance	$R_{DS(\text{ON})}$	$V_{GS}=10\text{V}, I_D=5.8\text{A}$		22.8	28	$\text{m}\Omega$
		$V_{GS}=10\text{V}, I_D=5.8\text{A}, T_J=125^\circ\text{C}$		32	39	
		$V_{GS}=4.5\text{V}, I_D=5\text{A}$		27.3	33	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=4\text{A}$		43.3	52	$\text{m}\Omega$
On state drain current	$I_{D(\text{ON})}$	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	30			A
Forward Transconductance	g_{FS}	$V_{DS}=5\text{V}, I_D=5\text{A}$	10	15		S
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		823	1050	pF
Output Capacitance	C_{oss}			99		pF
Reverse Transfer Capacitance	C_{rss}			77		pF
Gate resistance	R_g	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		1.4	3.6	Ω
Total Gate Charge	Q_g	$V_{GS}=4.5\text{V}, V_{DS}=15\text{V}, I_D=5.8\text{A}$		9.7	12	nC
Gate Source Charge	Q_{gs}			1.6		nC
Gate Drain Charge	Q_{gd}			3.1		nC
Turn-On DelayTime	$t_{D(\text{on})}$	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=2.7\Omega, R_{GEN}=3\Omega$		3.3	5	ns
Turn-On Rise Time	t_r			4.8	7	ns
Turn-Off DelayTime	$t_{D(\text{off})}$			26.3	40	ns
Turn-Off Fall Time	t_f			4.1	6	ns
Body Diode Reverse Recovery Time	t_{rr}	$I_F=5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		16	20	ns
Body Diode Reverse Recovery Charge	Q_{rr}	$I_F=5\text{A}, dI/dt=100\text{A}/\mu\text{s}$		8.9	12	nC
Maximum Body-Diode Continuous Current	I_S				2.5	A
Diode Forward Voltage	V_{SD}	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.71	1	V

■ Marking

Marking	KA6
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2KK5006DS

■ Typical Characteristics

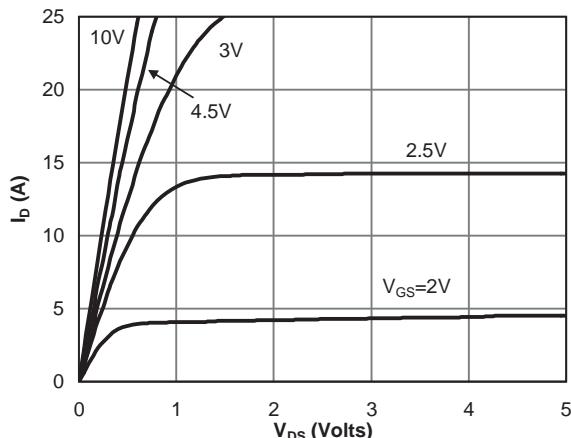


Fig 1: On-Region Characteristics

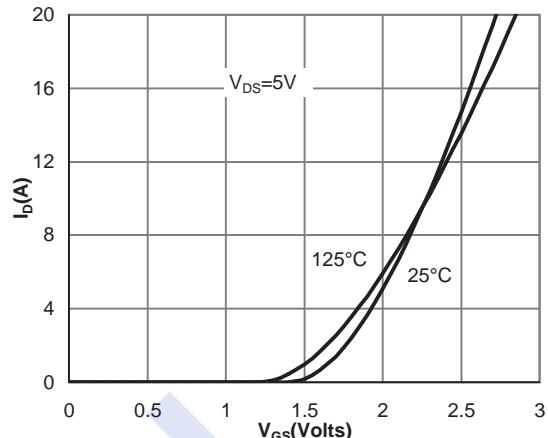


Figure 2: Transfer Characteristics

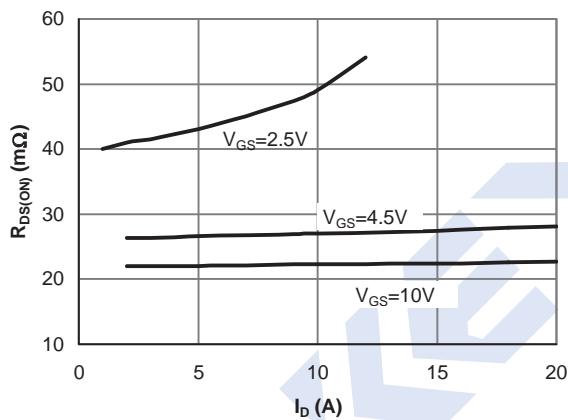


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

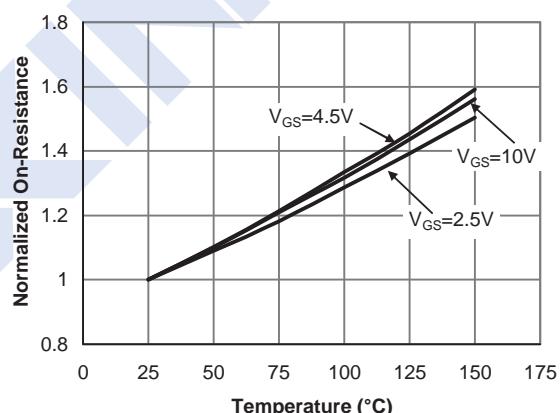


Figure 4: On-Resistance vs. Junction Temperature

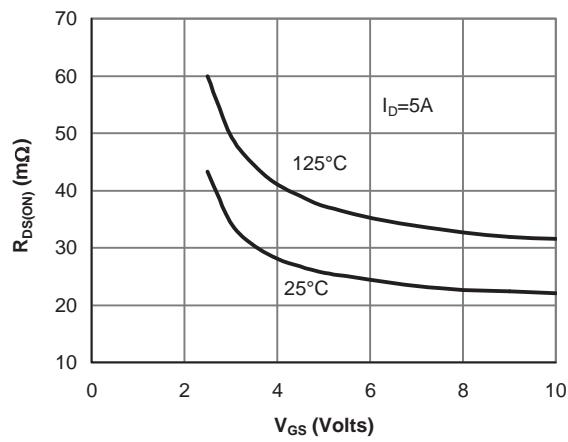


Figure 5: On-Resistance vs. Gate-Source Voltage

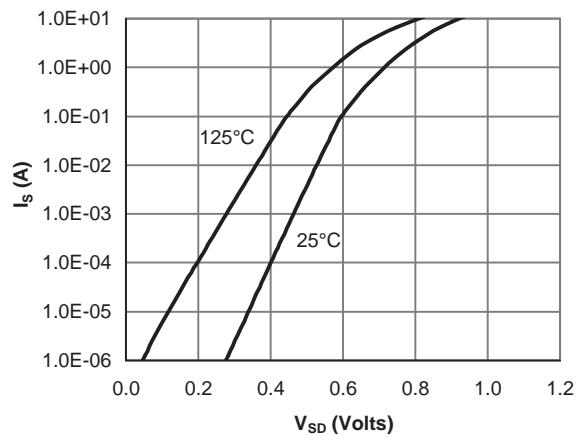


Figure 6: Body-Diode Characteristics

2KK5006DS

■ Typical Characteristics

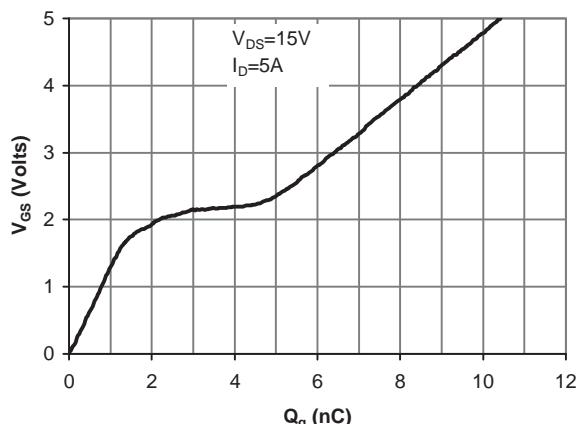


Figure 7: Gate-Charge Characteristics

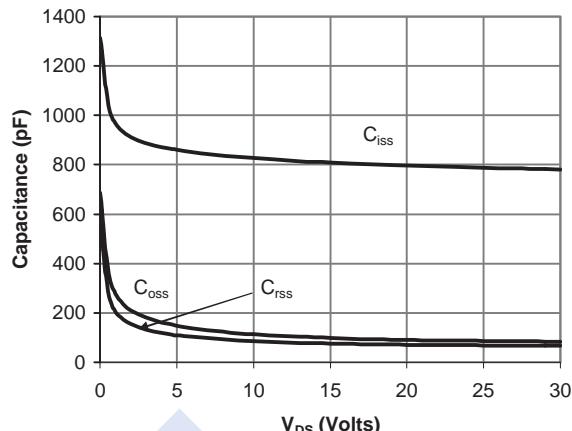


Figure 8: Capacitance Characteristics

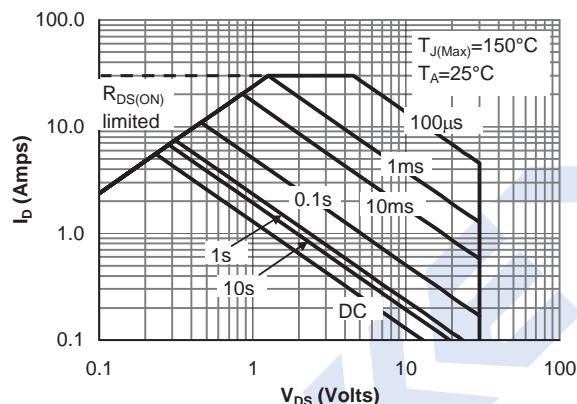


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

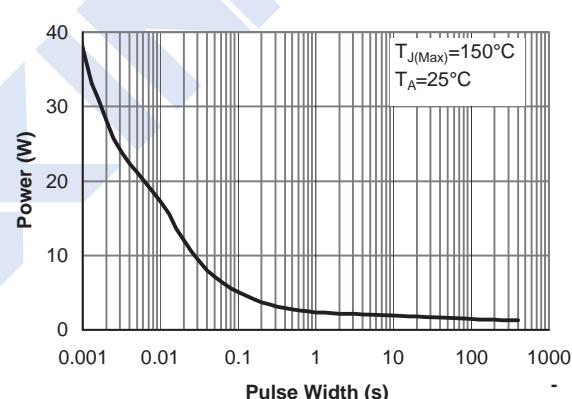


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

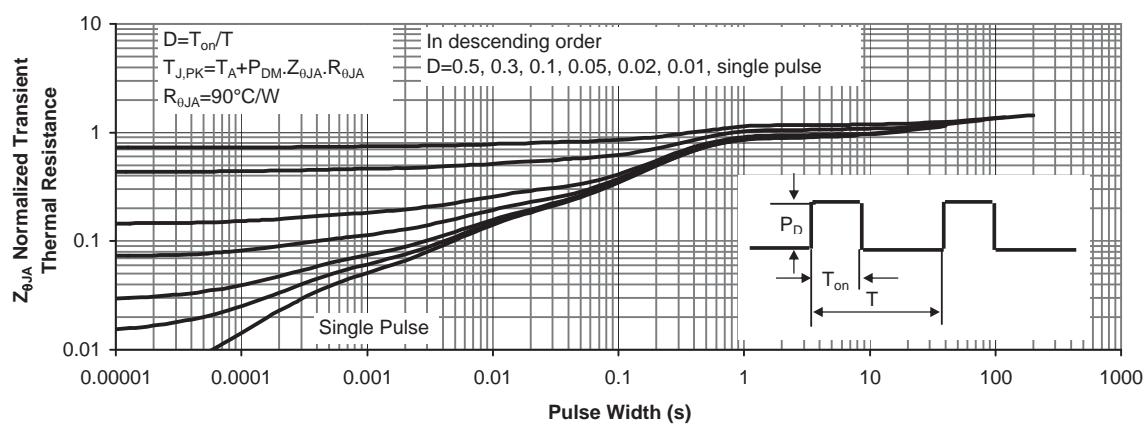


Figure 11: Normalized Maximum Transient Thermal Impedance